

Search Notes

Application/Control No.

10/733,339

Examiner

Y. J. Han

Applicant(s)/Patent under
Reexamination

TOBITA, ATSUHIRO

Art Unit

2838

SEARCHED

Class	Subclass	Date	Examiner
363	16		
	19		
	21.08		
	21.1		
	21.16		
	21.18		
	97		
	131	6/05	gA

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner